

**Search Notes**

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Examiner

Tam Nguyen

Applicant(s)/Patent under  
Reexamination

CHAE, HEE-SEON

Art Unit

3764

**SEARCHED**

Class	Subclass	Date	Examiner
482	51-53,62, 70,73,79, 95,96,131	7/24/2006	TN
482	136,142	7/24/2006	TN
482	146,147	7/24/2006	TN
D21	688,689	7/24/2006	TN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
482	51,146	7/24/2006	TN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Interference Search History Report	7/24/2006	TN